

## SN74AHC1G00-Q1 車載対応、シングル 2 入力正論理 NAND ゲート

### 1 特長

- 車載アプリケーション向け認定済み
- 動作範囲: 2V~5.5V
- 最大  $t_{pd}$  6.5ns (5V 時)
- 低消費電力、最大  $I_{CC}$  10 $\mu$ A
- 5V で  $\pm 8$ mA の出力駆動能力
- 全入力でのシュミット・トリガ・アクションにより、低速の入力立ち上がり / 立ち下がり時間を許容

### 2 アプリケーション

- デジタル信号のイネーブルまたはディセーブル
- インジケータ LED の制御
- 通信モジュールとシステム・コントローラの間の変換



論理図 (正論理)

### 3 概要

SN74AHC1G00-Q1 は、ブール関数  $Y = \overline{A \cdot B}$ 、つまり  $Y = \overline{A} + \overline{B}$  を正論理で実行します。

#### パッケージ情報

部品番号	パッケージ (1)	パッケージ・サイズ (2)	本体サイズ (3)
SN74AHC1G00-Q1	DBV (SOT-23, 5)	2.9mm × 2.8mm	2.9mm × 1.6mm
	DCK (SOT-SC70, 5)	2mm × 2.1mm	2mm × 1.25mm

- (1) 利用可能なすべてのパッケージについては、データシートの末尾にある注文情報を参照してください。
- (2) パッケージ・サイズ (長さ×幅) は公称値であり、該当する場合はピンも含まれます。
- (3) 本体サイズ (長さ×幅) は公称値であり、ピンは含まれません。



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## 4 Revision History

### Changes from Revision B (February 2008) to Revision C (October 2023)

	Page
• 「アプリケーション」、「パッケージ情報」表、「ピンの機能」表、「ESD 定格」表、「熱に関する情報」表、「デバイスの機能モード」、「アプリケーションと実装」セクション、「デバイスおよびドキュメントのサポート」セクション、および「メカニカル、パッケージ、および注文情報」セクションを追加.....	1
• 「パッケージ情報」表に DBV パッケージを追加.....	1
• Added DBV package to <i>Pin Configuration and Functions</i> section.....	3
• Added the thermal value for the DBV package: R $\theta$ JA = 278.0 °C/W. Updated the thermal value for the DCK package: R $\theta$ JA = 293.4 °C/W. ....	5

## 5 Pin Configuration and Functions

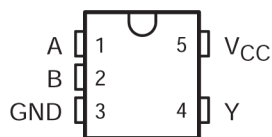


図 5-1. DBV Package, SOT-23; DCK Package, 5-Pin SOT SC-70 (Top View)

表 5-1. Pin Functions

PIN		TYPE	DESCRIPTION
NO.	NAME		
1	A	I	Input A
2	B	I	Input B
3	GND	—	Ground Pin
4	Y	O	Output Y
5	V <sub>CC</sub>	—	Power Pin

## 6 Specifications

### 6.1 Absolute Maximum Ratings

over recommended operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		MIN	MAX	UNIT
$V_{CC}$	Supply voltage range	-0.5	7	V
$V_I$ <sup>(2)</sup>	Input voltage range	-0.5	7	V
$V_O$ <sup>(2)</sup>	Output voltage range	-0.5	$V_{CC} + 0.5$	V
$I_{IK}$	Input clamp current	$(V_I < 0)$		-20 mA
$I_{OK}$	Output clamp current	$(V_O < 0 \text{ or } V_O > V_{CC})$		±20 mA
$I_O$	Continuous output current	$(V_O = 0 \text{ to } V_{CC})$		±25 mA
	Continuous current through $V_{CC}$ or GND			±50 mA
$T_{stg}$	Storage temperature range	-65	150	°C

- (1) Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

### 6.2 ESD Ratings

		VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±2000
		Charged device model (CDM), per AEC Q100-011	±1000

- (1) AEC Q100-002 indicates that HBM stressing must be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

### 6.3 Recommended Operating Conditions

over recommended operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		MIN	MAX	UNIT
$V_{CC}$	Supply voltage	2	5.5	V
$V_{IH}$	High-level input voltage	$V_{CC} = 2 \text{ V}$	1.5	V
		$V_{CC} = 3 \text{ V}$	2.1	
		$V_{CC} = 5.5 \text{ V}$	3.85	
$V_{IL}$	Low-level input voltage	$V_{CC} = 2 \text{ V}$	0.5	V
		$V_{CC} = 3 \text{ V}$	0.9	
		$V_{CC} = 5.5 \text{ V}$	1.65	
$V_I$	Input voltage	0	5.5	V
$V_O$	Output voltage	0	$V_{CC}$	V
$I_{OH}$	High-level output current	$V_{CC} = 2 \text{ V}$	-50	μA
		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	-4	mA
		$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	-8	
$I_{OL}$	Low-level output current	$V_{CC} = 2 \text{ V}$	50	μA
		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	4	mA
		$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	8	
$\Delta t/\Delta v$	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	100	ns/V
		$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$	20	
$T_A$	Operating free-air temperature	-40	125	°C

- (1) All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

## 6.4 Thermal Information

THERMAL METRIC <sup>(1)</sup>	SN74AHC1G00-Q1		UNIT
	DBV	DCK	
	5 PINS	5 PINS	
$R_{\theta JA}$ Junction-to-ambient thermal resistance	278.0	293.4	°C/W

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report ([SPRA953](#)).

## 6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	$T_A = 25^\circ\text{C}$			$-40^\circ\text{C TO } 125^\circ\text{C}$		UNIT
			MIN	TYP	MAX	MIN	MAX	
$V_{OH}$	$I_{OH} = -50\ \mu\text{A}$	2 V	1.9	2		1.9		V
		3 V	2.9	3		2.9		
		4.5 V	4.4	4.5		4.4		
	$I_{OH} = -4\ \text{mA}$	3 V	2.58			2.48		
	$I_{OH} = -8\ \text{mA}$	4.5 V	3.94			3.8		
$V_{OL}$	$I_{OL} = 50\ \mu\text{A}$	2 V			0.1		0.1	V
		3 V			0.1		0.1	
		4.5 V			0.1		0.1	
	$I_{OL} = 4\ \text{mA}$	3 V			0.36		0.5	
	$I_{OL} = 8\ \text{mA}$	4.5 V			0.36		0.5	
$I_I$	$V_I = 5.5\ \text{V or GND}$	0 V to 5.5 V			$\pm 0.1$		$\pm 1$	$\mu\text{A}$
$I_{CC}$	$V_I = V_{CC}\ \text{or GND}, I_O = 0$	5.5 V			1		10	$\mu\text{A}$
$C_i$	$V_I = V_{CC}\ \text{or GND}$	5 V		2	10		10	pF

## 6.6 Switching Characteristics, 3.3 V $\pm$ 0.3 V

over recommended operating free-air temperature range,  $V_{CC} = 3.3\ \text{V} \pm 0.3\ \text{V}$  (unless otherwise noted) (see [Load Circuit and Voltage Waveforms](#))

PARAMETER	FROM (INPUT)	TO (OUTPUT)	OUTPUT CAPACITANCE	$T_A = 25^\circ\text{C}$			$-40^\circ\text{C TO } 125^\circ\text{C}$		UNIT
				MIN	TYP	MAX	MIN	MAX	
$t_{PLH}$	A or B	Y	$C_L = 15\ \text{pF}$		5.5	7.9	1	11.5	ns
$t_{PHL}$					5.5	7.9	1	11.5	
$t_{PLH}$	A or B	Y	$C_L = 50\ \text{pF}$		8	11.4	1	15	ns
$t_{PHL}$					8	11.4	1	15	

## 6.7 Switching Characteristics, 5 V $\pm$ 0.5 V

over recommended operating free-air temperature range,  $V_{CC} = 5\text{ V} \pm 0.5\text{ V}$  (unless otherwise noted) (see [Load Circuit and Voltage Waveforms](#))

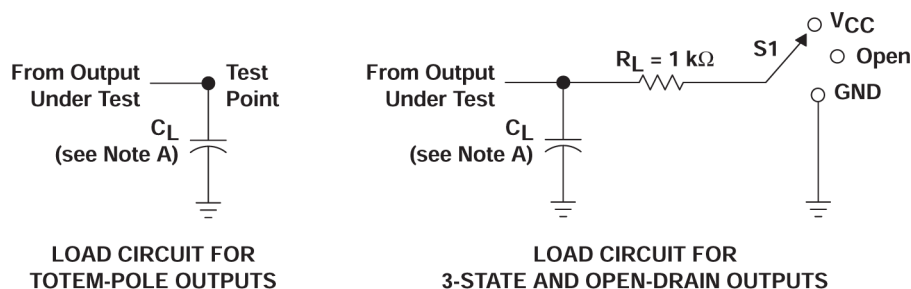
PARAMETER	FROM (INPUT)	TO (OUTPUT)	OUTPUT CAPACITANCE	$T_A = 25^\circ\text{C}$			$-40^\circ\text{C TO } 125^\circ\text{C}$		UNIT
				MIN	TYP	MAX	MIN	MAX	
$t_{PLH}$	A or B	Y	$C_L = 15\text{ pF}$		3.7	5.5	1	8.5	ns
$t_{PHL}$					3.7	5.5	1	8.5	
$t_{PLH}$	A or B	Y	$C_L = 50\text{ pF}$		5.2	7.5	1	10.5	ns
$t_{PHL}$					5.2	7.5	1	10.5	

## 6.8 Operating Characteristics

$V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$

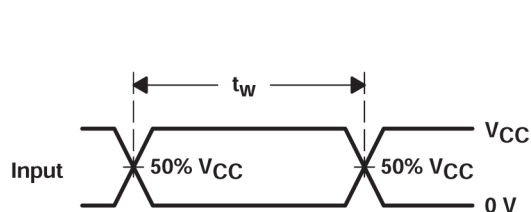
PARAMETER		TEST CONDITIONS		TYP	UNIT
$C_{pd}$	Power dissipation capacitance	No load,	$f = 1\text{ MHz}$	9.5	pF

## 7 Parameter Measurement Information

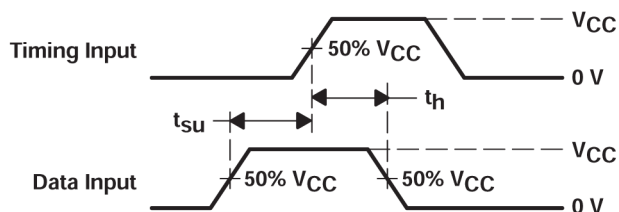


LOAD CIRCUIT FOR  
TOTEM-POLE OUTPUTS

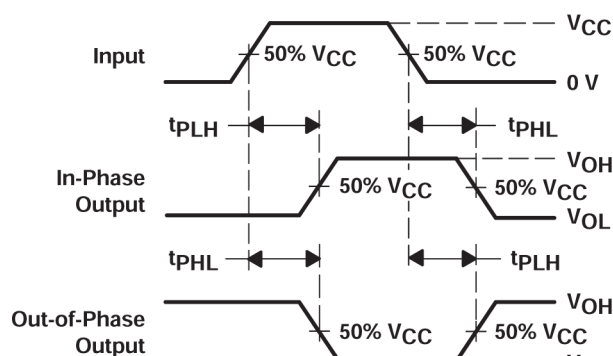
LOAD CIRCUIT FOR  
3-STATE AND OPEN-DRAIN OUTPUTS



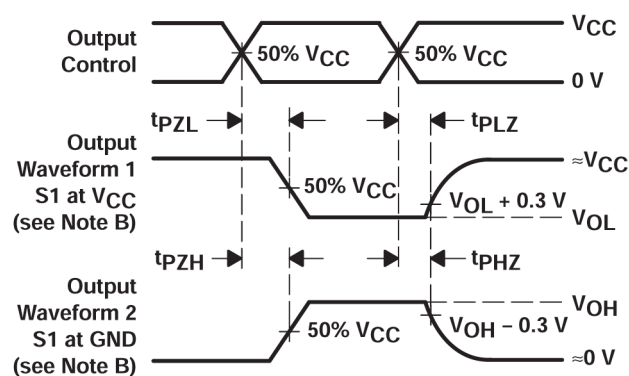
VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES  
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES  
LOW- AND HIGH-LEVEL ENABLING

- A.  $C_L$  includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 1\text{ MHz}$ ,  $Z_O = 50\ \Omega$ ,  $t_r \leq 3\text{ ns}$ ,  $t_f \leq 3\text{ ns}$ .
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. All parameters and waveforms are not applicable to all devices.

✎ 7-1. Load Circuit and Voltage Waveforms

TEST	S1
$t_{PLH}/t_{PHL}$	Open
$t_{PLZ}/t_{PZL}$	$V_{CC}$
$t_{PHZ}/t_{PZH}$	GND
Open Drain	$V_{CC}$

## 8 Detailed Description

### 8.1 Overview

The SN74AHC1G00-Q1 contains four independent 2-input AND Gates with Schmitt-trigger inputs. Each gate performs the Boolean function  $Y = A \times B$  in positive logic. The output level is referenced to the supply voltage ( $V_{CC}$ ) and supports 1.8-V, 2.5-V, 3.3-V, and 5-V CMOS levels.

### 8.2 Functional Block Diagram



図 8-1. Logic Diagram (Positive Logic)

### 8.3 Device Functional Modes

表 8-1. Function Table

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

## 9 Application and Implementation

### 注

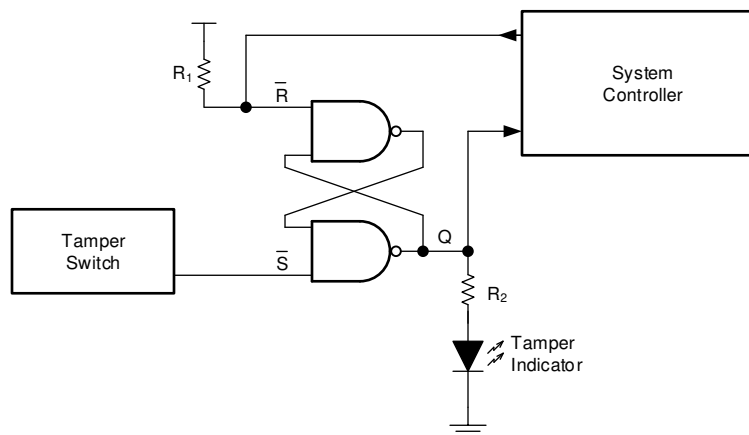
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

### 9.1 Application Information

In this application, two 2-input NAND gates are used to create an active-low SR latch as shown in [Figure 9-1](#). The two additional gates can be used for a second SR latch, or the inputs can be grounded and both channels left unused.

The SN74AHC1G00-Q1 is used to drive the tamper indicator LED and provide one bit of data to the system controller. When the tamper switch outputs LOW, the output Q becomes HIGH. This output remains HIGH until the system controller addresses the event and sends a LOW signal to the R input which returns the Q output back to LOW.

### 9.2 Typical Application



**Figure 9-1. Typical application block diagram**

### 9.3 Design Requirements

### 9.4 Detailed Design Procedure

1. Add a decoupling capacitor from  $V_{CC}$  to GND. The capacitor needs to be placed physically close to the device and electrically close to both the  $V_{CC}$  and GND pins. An example layout is shown in the [Layout](#).
2. Ensure the capacitive load at the output is  $\leq 70$  pF. This is not a hard limit, however it will ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the SN74HC00-Q1 to the receiving device.
3. Ensure the resistive load at the output is larger than  $(V_{CC} / I_{O(max)}) \Omega$ . This will ensure that the maximum output current from the [Section 6.1](#) is not violated. Most CMOS inputs have a resistive load measured in megaohms; much larger than the minimum calculated above.
4. Thermal issues are rarely a concern for logic gates, however the power consumption and thermal increase can be calculated using the steps provided in the application report, [CMOS Power Consumption and Cpd Calculation](#)

## 9.5 Application Curves

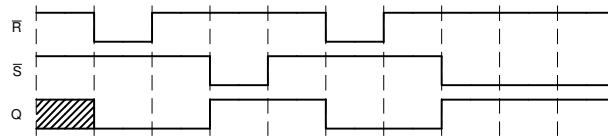


図 9-2. Application timing diagram

## 9.6 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu\text{F}$  capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1- $\mu\text{F}$  and 1- $\mu\text{F}$  capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in the following layout example.

## 9.7 Layout

### 9.7.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused (for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used). Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

### 9.7.2 Layout Example

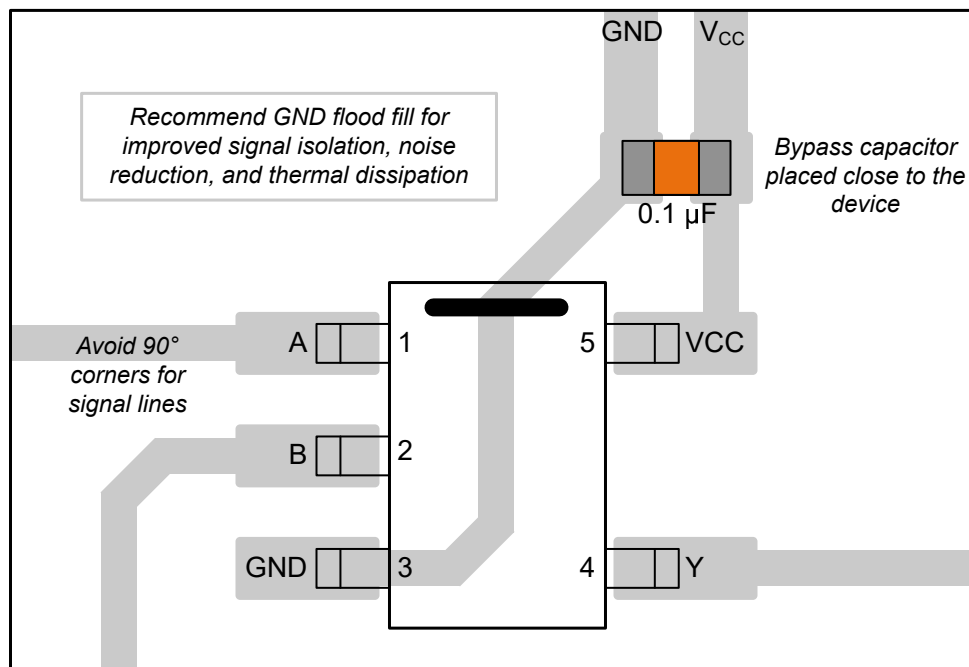


図 9-3. Example Layout for the SN74AHC1G00-Q1

## 10 Device and Documentation Support

### 10.1 Documentation Support (Analog)

#### 10.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, [CMOS Power Consumption and Cpd Calculation application note](#)
- Texas Instruments, [Designing With Logic application note](#)
- Texas Instruments, [Thermal Characteristics of Standard Linear and Logic \(SLL\) Packages and Devices application note](#)
- Texas Instruments, [Implications of Slow or Floating CMOS Inputs application note](#)

### 10.2 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、[www.tij.co.jp](http://www.tij.co.jp) のデバイス製品フォルダを開いてください。[通知] をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取ることができます。変更の詳細については、改訂されたドキュメントに含まれている改訂履歴をご覧ください。

### 10.3 サポート・リソース

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### 10.4 Trademarks

テキサス・インスツルメンツ E2E™ is a trademark of Texas Instruments.

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### 10.5 静電気放電に関する注意事項



この IC は、ESD によって破損する可能性があります。テキサス・インスツルメンツは、IC を取り扱う際には常に適切な注意を払うことを推奨します。正しい取り扱いおよび設置手順に従わない場合、デバイスを破損するおそれがあります。

ESD による破損は、わずかな性能低下からデバイスの完全な故障まで多岐にわたります。精密な IC の場合、パラメータがわずかに変化するだけで公表されている仕様から外れる可能性があるため、破損が発生しやすくなっています。

### 10.6 用語集

[テキサス・インスツルメンツ用語集](#) この用語集には、用語や略語の一覧および定義が記載されています。

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

## PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN74AHC1G00DBVRQ1	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 125	36CH	<a href="#">Samples</a>
SN74AHC1G00QDCKRQ1	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AAU	<a href="#">Samples</a>

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

**OTHER QUALIFIED VERSIONS OF SN74AHC1G00-Q1 :**

- Catalog : [SN74AHC1G00](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product

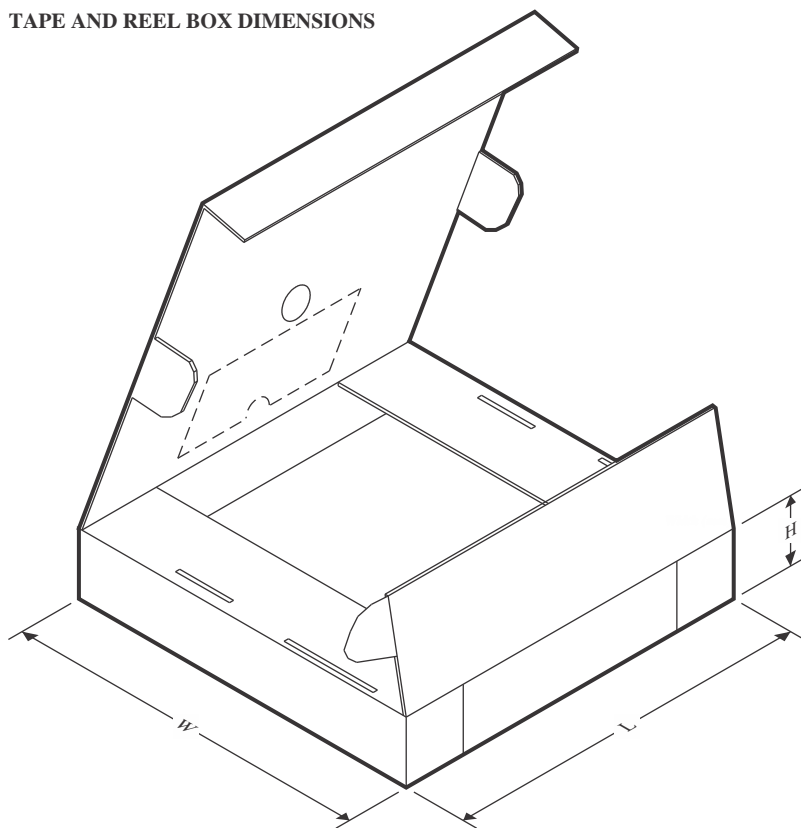
## TAPE AND REEL INFORMATION



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHC1G00DBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74AHC1G00QDCKRQ1	SC70	DCK	5	3000	179.0	8.4	2.2	2.5	1.2	4.0	8.0	Q3

## TAPE AND REEL BOX DIMENSIONS



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHC1G00DBVRQ1	SOT-23	DBV	5	3000	210.0	185.0	35.0
SN74AHC1G00QDCKRQ1	SC70	DCK	5	3000	200.0	183.0	25.0



## SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



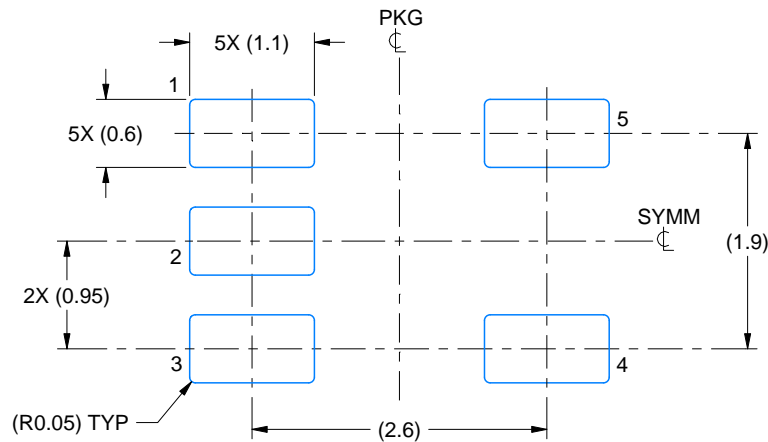
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Reference JEDEC MO-178.
4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
5. Support pin may differ or may not be present.

# EXAMPLE BOARD LAYOUT

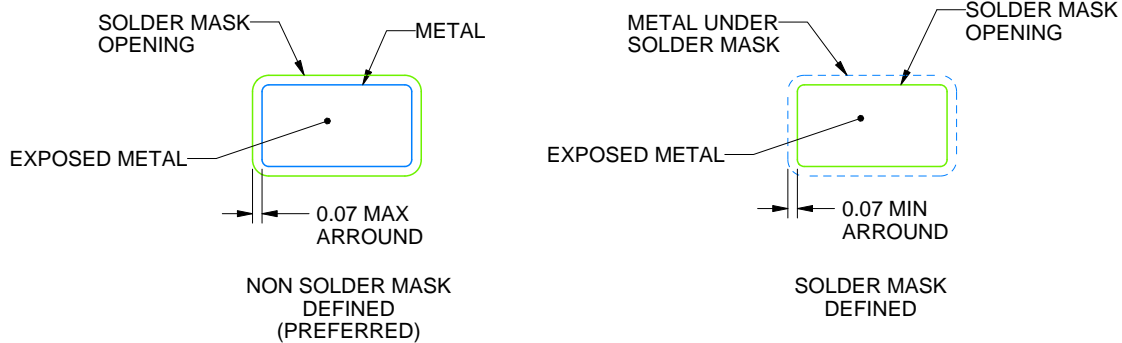
DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



LAND PATTERN EXAMPLE  
EXPOSED METAL SHOWN  
SCALE:15X



SOLDER MASK DETAILS

4214839/J 02/2024

NOTES: (continued)

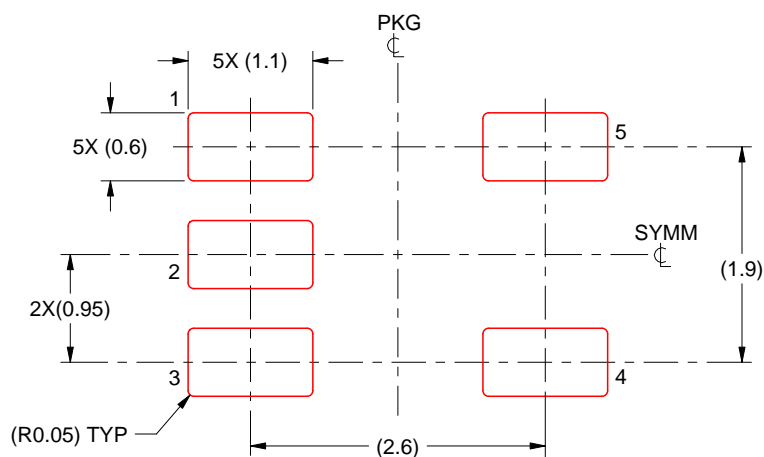
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

## EXAMPLE STENCIL DESIGN

DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR

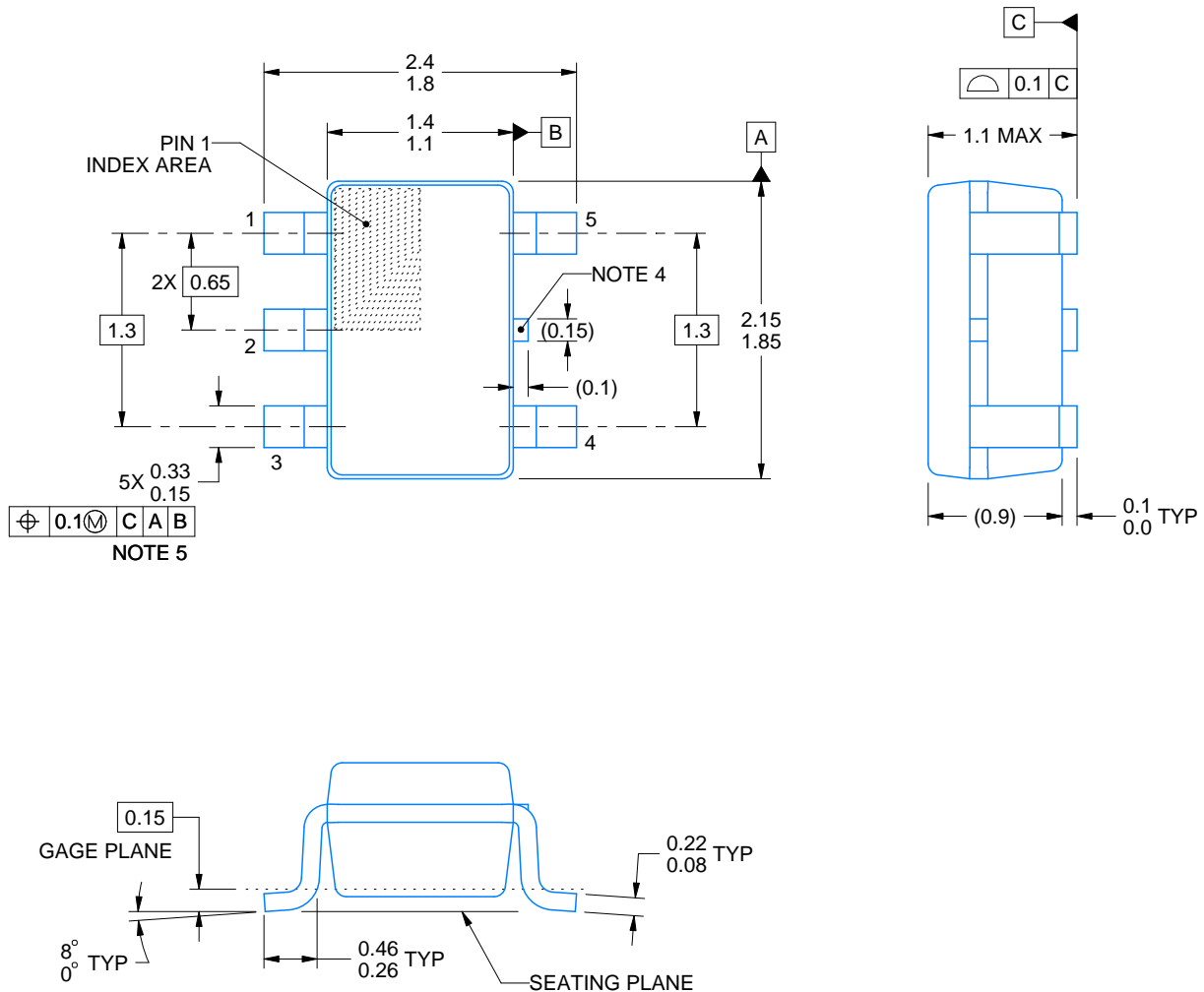


SOLDER PASTE EXAMPLE  
BASED ON 0.125 mm THICK STENCIL  
SCALE:15X

4214839/J 02/2024

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.



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## NOTES:

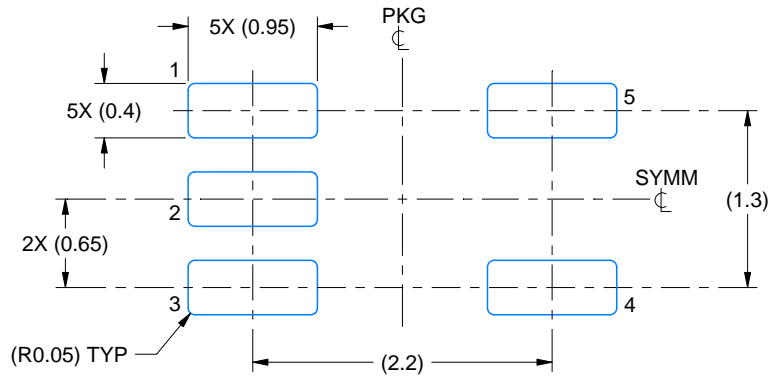
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Reference JEDEC MO-203.
4. Support pin may differ or may not be present.
5. Lead width does not comply with JEDEC.

# EXAMPLE BOARD LAYOUT

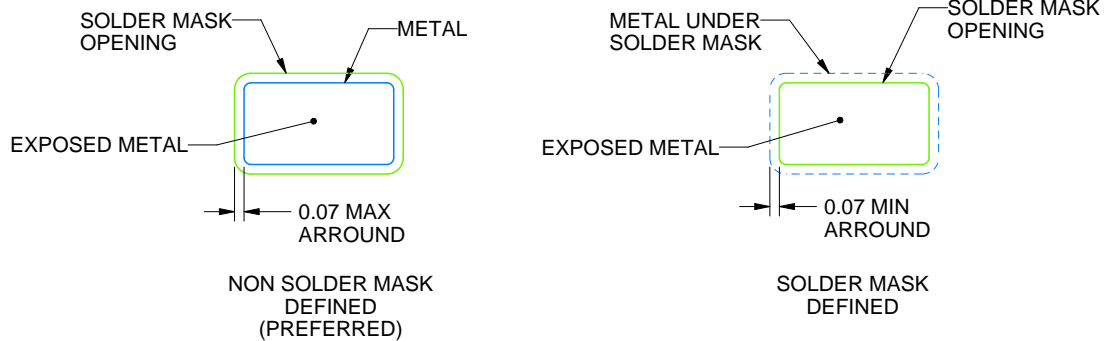
DCK0005A

SOT - 1.1 max height

SMALL OUTLINE TRANSISTOR



LAND PATTERN EXAMPLE  
EXPOSED METAL SHOWN  
SCALE:18X

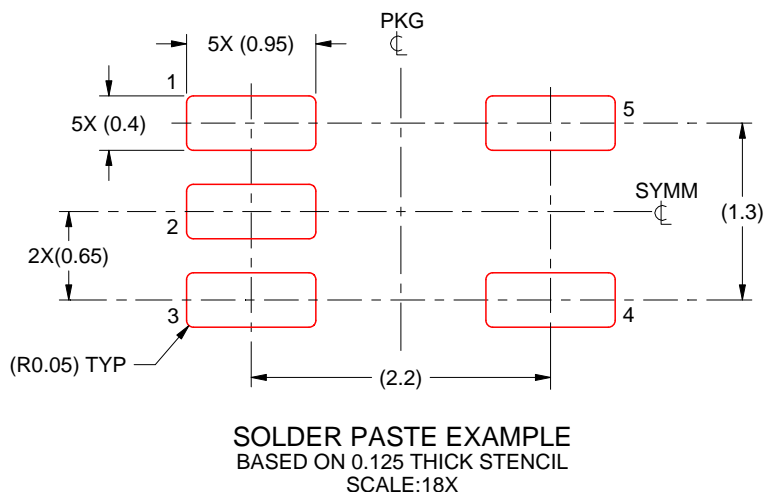


SOLDER MASK DETAILS

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NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



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NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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